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Titel: TESTING

Zusammenfassung

PURPOSE: To make it possible to bring a testing terminal into highly precise electric contact with each chip and thereby to increase a testing accuracy and a testing efficiency by deciding the amount of movement of a stage at the time of positioning the testing terminal based on the parameter obtained from the positional data special to a substrate and each test piece.

CONSTITUTION: A testing terminal is positioned by stages 51-54 which can move in the X-Y-Z-θ directions and the testing is conducted by bringing the testing terminal into contact with an electrode terminal of each of a plurality of test pieces installed on a substrate 3. In such a testing method, the amount of movement of the stages 51-54 is decided based on the parameter obtained from the positional data special to the substrate 3 and each test piece when positioning the testing terminal. For example the coordinate data as to the substrate 3 is preliminarily measured and the data is given as the parameter of the command on the semiconductor testing device side. The positioning of the testing terminal is conducted using the parameter and the measuring results by each alignment camera 18a, 18b, 23, 55.

